



LFW

MNDSPD.002

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Mark Lynch) Group Art Unit: 2829
App. No. : 10/810,789)
Filed : March 26, 2004)
For : METHOD AND APPARATUS FOR)
PACKAGE TESTING)
Examiner : Unknown)

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

August 6, 2004
(Date)

Chad W. Miller, Reg. No. 44,943

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing references that are also enclosed. This Information Disclosure Statement is being filed before the mailing of the first Office Action on the merits, and as such, no fee is required in accordance with 37 C.F.R. § 1.97(b)(3).

Respectfully submitted,

Dated: 8/6/04By: C. Miller

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MNDSPD.0027P	APPLICATION NO. 10/810,789
	APPLICANT Mark Lynch	
	FILING DATE March 26, 2004	GROUP 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	FlipChips Dot Com "Tutorial 2 - Solder Bump Flip Chip", http://www.flipchips.com/tutorial102a.html , 7 pages "Highly Accelerated Stress Test (HAST)", © 1991-2001 Innovative Circuits Engineering, Inc., 1 page
	"HAST (Highly Accelerated Stress Testing)", © 2003 Environ Laboratoies, Inc., 2 pages "What is HAST?-- Introduction", © 2003, ESPEC NORTH AMERICA, INC., 2 pages
	"What is HAST?-- Principles of High Humidity", © 2003, ESPEC NORTH AMERICA, INC., 2 pages "What is HAST?-- Test Equipment", © 2003, ESPEC NORTH AMERICA, INC., 6 pages
	"What is HAST? -- Testing Techniques", © 2003, ESPEC NORTH AMERICA, INC., 2 pages "What is HAST?-- Reliability Analysis", © 2003, ESPEC NORTH AMERICA, INC., 2 pages

EXAMINER	DATE CONSIDERED
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